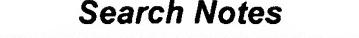


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/615,229	ITOI ET AL.
	Examiner	Art Unit
	Y. Lee	2621

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	240.26	1/30/2008	YL